

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

Takashi KOBAYASHI et al.

Appln. No.:

Filed: Herewith

For: NONVOLATILE SEMICONDUCTOR MEMORY DEVICE AND  
MANUFACTURING METHOD THEREOF

\* \* \*

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:


Pursuant to 37 C.F.R. § 1.56, and without any  
assertion as to materiality or prior art effect, the  
documents listed on the attached Form PTO-1449 are hereby  
cited.

The documents on the attached List were cited in the  
specification, on pages 1, 2, 28, and 35, and their  
relevance is indicated therein.

Respectfully submitted,

MWS:lat

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By:   
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Reg. No. 31,568

November 24, 2003

|   |    |                    |                |  |       |            |                 |
|---|----|--------------------|----------------|--|-------|------------|-----------------|
| <b>FORM PTO-1449</b>  |    |                    |                | Atty. Docket No.<br><b>XA-9997</b>           |       | Appln. No. |                 |
| <b><u>LIST OF DOCUMENTS CITED BY APPLICANT</u></b>  |    |                    |                |  |       |            |                 |
|   |    |                    |                | Applicant<br><b>Takashi KOBAYASHI et al.</b> |       |            |                 |
|   |    |                    |                | Filing Date<br><b>HEREWITH</b>               |       | Group      |                 |
| <b>U.S. PATENT DOCUMENTS</b>  |    |                    |                |  |       |            |                 |
| Examiner Initial  |    | Document Number    | Date           | Name   | Class | Sub-class  | Filing Date     |
|   | AA |                    |                |  |       |            |                 |
|   | AB |                    |                |  |       |            |                 |
|   | AC |                    |                |  |       |            |                 |
|   | AD |                    |                |  |       |            |                 |
|   | AE |                    |                |  |       |            |                 |
|   | AF |                    |                |  |       |            |                 |
|   | AG |                    |                |  |       |            |                 |
|   | AH |                    |                |  |       |            |                 |
|   | AI |                    |                |  |       |            |                 |
| <b>FOREIGN PATENT DOCUMENTS</b>   |    |                    |                |  |       |            |                 |
| Examiner Initial  |    | Document Number    | Date           | Country                                      | Class | Sub-class  | Translation     |
|   | AJ | <b>2001-028428</b> | <b>1/30/01</b> | <b>Japan</b>                                 |       |            | <b>Abstract</b> |
|   | AK | <b>2001-085541</b> | <b>3/30/01</b> | <b>Japan</b>                                 |       |            | <b>Abstract</b> |
|   | AL |                    |                |  |       |            |                 |
|   | AM |                    |                |  |       |            |                 |
|   | AN |                    |                |  |       |            |                 |
|   | AO |                    |                |  |       |            |                 |
| <b>OTHER</b> (including author, title, date, pertinent pages, etc.)   |    |                    |                |  |       |            |                 |
|   | AP |                    |                |  |       |            |                 |
|   | AQ |                    |                |  |       |            |                 |
|   | AR |                    |                |  |       |            |                 |
| Examiner  |    |                    |                | Date Considered                              |       |            |                 |
| XAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant. |    |                    |                |  |       |            |                 |